

ABSTRACT

In a first aspect, a first method is provided for testing an integrated circuit (IC). The first method includes the steps of (1) employing one of a plurality of input lines to receive a test signal for a processor; (2) employing one of a plurality of output lines to send a test result from the processor; and (3) if the test result is unsuccessful, performing at least one of employing a remaining one of the plurality of input lines to receive the test signal for the processor and employing a remaining one of the plurality of output lines to send the test result from the processor. Numerous other aspects are provided.